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| Notice of References Cited | Application/Control No. 09/729,694 | Applicant(s)/Patent Under Reexamination YANG ET AL. | |
| | Examiner Sudhanshu C. Pathak | Art Unit 2634 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-4,317,229 | 02-1982 | Craig et al. | 455/277.1 |
| | B | US-5,565,873 | 10-1996 | Dean, Stuart J. | 342/372 |
| | C | US-6,115,406 | 09-2000 | Mesecher, David K. | 375/130 |
| | D | US-6,347,220 | 02-2002 | Tanaka et al. | 455/277.2 |
| | E | US-6,345,188 | 02-2002 | Keskitalo et al. | 455/561 |
| | F | US-5,819,182 | 10-1998 | Gardner et al. | 455/524 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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